

January 2015

FDMS0309AS

N-Channel PowerTrench[®] SyncFETTM 30 V, 49 A, 3.5 m Ω

Features

- Max $r_{DS(on)} = 3.5 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 21 \text{ A}$
- Max $r_{DS(on)} = 4.3 \text{ m}\Omega$ at $V_{GS} = 4.5 \text{ V}$, $I_D = 19 \text{ A}$
- Advanced package and silicon combination for low r_{DS(on)} and high efficiency
- SyncFETTM Schottky Body Diode
- MSL1 Robust Package Design
- 100% UIL tested
- RoHS Compliant

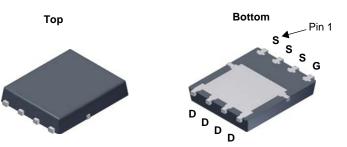


General Description

The FDMS0309AS has been designed to minimize losses in power conversion application. Advancements in both silicon and package technologies have been combined to offer the lowest $r_{\text{DS}(\text{on})}$ while maintaining excellent switching performance.This device has the added benefit of an efficient monolithic Schottky body diode.

Applications

- Synchronous Rectifier for DC/DC Converters
- Notebook Vcore/GPU Low Side Switch
- Networking Point of Load Low Side Switch
- Telecom Secondary Side Rectification



Power 56

D 5 4 G D 6 3 S D 7 2 S D 8 1 S

MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Parameter		Ratings	Units	
V _{DS}	Drain to Source Voltage		30	V	
V _{DSt}	Drain to Source Transient Voltage (tTransient	< 100 ns)		33	V
V_{GS}	Gate to Source Voltage		(Note 4)	±20	V
	Drain Current -Continuous (Package limited)	T _C = 25°C		49	
	-Continuous (Silicon limited) $T_C = 25$ °C			96	A
I _D	-Continuous	T _A = 25°C	(Note 1a)	21	A
	-Pulsed			100	
E _{AS}	Single Pulse Avalanche Energy		(Note 3)	66	mJ
D	Power Dissipation	T _C = 25°C		50	W
P_{D}	Power Dissipation	T _A = 25°C	(Note 1a)	2.5	VV
T _J , T _{STG}	Operating and Storage Junction Temperature Ra	Operating and Storage Junction Temperature Range			°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case	2.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	50	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS0309AS	FDMS0309AS	Power 56	13 "	12 mm	3000 units

Electrical Characteristics $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
BV_{DSS}	Drain to Source Breakdown Voltage	I _D = 1 mA, V _{GS} = 0 V	30			V
$\frac{\Delta BV_{DS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I _D = 10 mA, referenced to 25 °C		25		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 24 V, V _{GS} = 0 V			500	μΑ
I _{GSS}	Gate to Source Leakage Current, Forward	V _{GS} = 20 V, V _{DS} = 0 V			100	nA

On Characteristics

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 1$ mA	1.2	1.6	3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I _D = 10 mA, referenced to 25 °C		-5		mV/°C
		V _{GS} = 10 V, I _D = 21 A		2.7	3.5	mΩ
r	Static Drain to Source On Resistance	$V_{GS} = 4.5 \text{ V}, I_D = 19 \text{ A}$		3.4	4.3	
r _{DS(on)} Static Drain to Source On Resistance	Static Drain to Source Of Nesistance	$V_{GS} = 10 \text{ V, } I_D = 21 \text{ A,}$ $T_J = 125 \text{ °C}$		3.7	4.8	11122
9 _{FS}	Forward Transconductance	V _{DS} = 5 V, I _D = 21 A		120		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 45 V V 0 V	2255	3000	pF
Coss	Output Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1 MHz	815	1085	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1 101112	85	125	pF
R_g	Gate Resistance		1.0	2.5	Ω

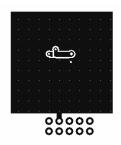
Switching Characteristics

t _{d(on)}	Turn-On Delay Time		11	19	ns
t _r	Rise Time	V _{DD} = 15 V, I _D = 21 A,	4.5	10	ns
t _{d(off)}	Turn-Off Delay Time	V_{GS} = 10 V, R_{GEN} = 6 Ω	29	46	ns
t _f	Fall Time		3.7	10	ns
Q_g	Total Gate Charge	V _{GS} = 0 V to 10 V	34	47	nC
Q_g	Total Gate Charge	$V_{GS} = 0 \text{ V to } 4.5 \text{ V} V_{DD} = 15 \text{ V},$	16	23	nC
Q_{gs}	Gate to Source Charge	I _D = 21 A	5.9		nC
Q_{gd}	Gate to Drain "Miller" Charge		4.6		nC

Drain-Source Diode Characteristics

V _{SD} Source-Drain Diode Forward Voltage	Source Drain Diade Forward Voltage	$V_{GS} = 0 V, I_{S} = 2 A$ (Note 2)		0.6	0.8	\/
	$V_{GS} = 0 V, I_S = 21 A$ (Note 2)		0.8	1.2	V	
t _{rr}	Reverse Recovery Time	I _F = 21 A, di/dt = 300 A/μs		26	42	ns
Q _{rr}	Reverse Recovery Charge			27	44	nC

Notes:
1. R_{0JA} is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{0JC} is guaranteed by design while R_{0CA} is determined by the user's board design.



a. 50 °C/W when mounted on a 1 in² pad of 2 oz copper.



b. 125 °C/W when mounted on a minimum pad of 2 oz copper.

^{2.} Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0%. 3. E_{AS} of 66 mJ is based on starting T_J = 25 °C, L = 0.3 mH, I_{AS} = 21 A, V_{DD} = 27 V, V_{GS} = 10 V 4. As an N-ch device, the negative Vgs rating is for low duty cycle pulse occurrence only. No continuous rating is implied.

Typical Characteristics T_{.1} = 25 °C unless otherwise noted

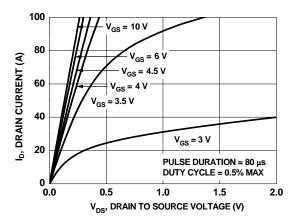


Figure 1. On Region Characteristics

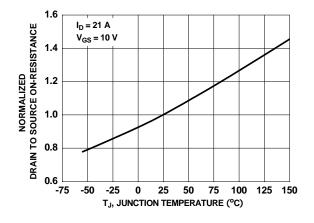


Figure 3. Normalized On Resistance vs Junction Temperature

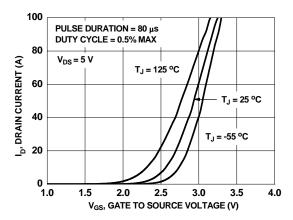


Figure 5. Transfer Characteristics

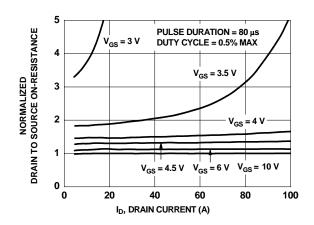


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

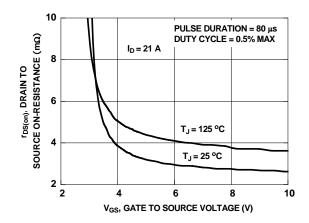


Figure 4. On-Resistance vs Gate to Source Voltage

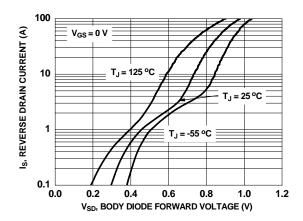


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics $T_J = 25$ °C unless otherwise noted

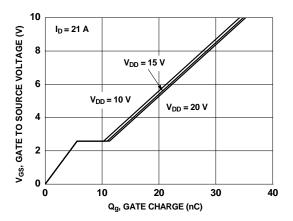


Figure 7. Gate Charge Characteristics

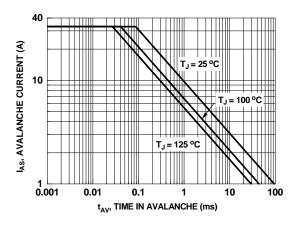


Figure 9. Unclamped Inductive Switching Capability

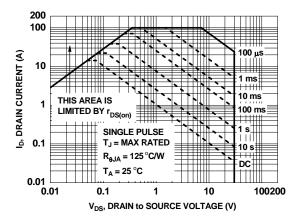


Figure 11. Forward Bias Safe Operating Area

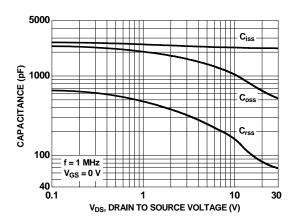


Figure 8. Capacitance vs Drain to Source Voltage

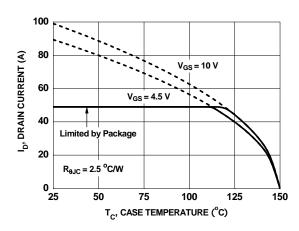


Figure 10. Maximum Continuous Drain Current vs Case Temperature

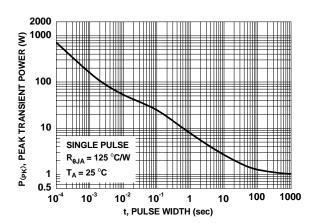


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics $T_J = 25$ °C unless otherwise noted

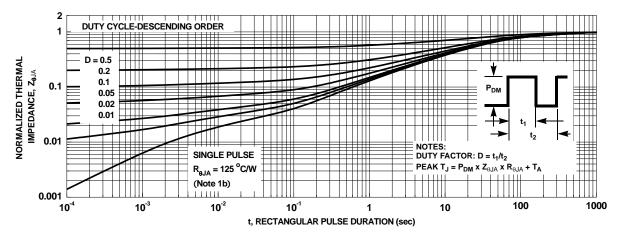


Figure 13. Junction-to-Ambient Transient Thermal Response Curve

Typical Characteristics (continued)

SyncFETTM Schottky body diode Characteristics

Fairchild's SyncFETTM process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 14 shows the reverse recovery characteristic of the FDMS0309AS.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

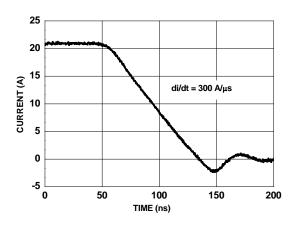


Figure 14. FDMS0309AS SyncFETTM body diode reverse recovery characteristic

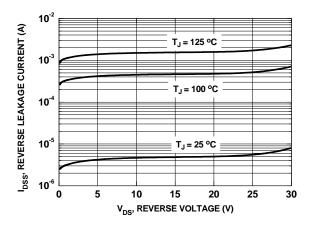


Figure 15. SyncFETTM body diode reverse leakage versus drain-source voltage







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